

Search Notes**Application/Control No.**

10/764,481

Examiner

MARK A. MAIS

Applicant(s)/Patent under Reexamination

HIYAMA ET AL.

Art Unit

2419

SEARCHED

Class	Subclass	Date	Examiner
370	310 328	11/20/2008	MAM
	329 331		
	338 351		
	352 353		
	389 392		
	401 469		
	474 475 476		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Search	Performed	Date	Examiner
		11/20/2008	MAM

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	6/16/2007	MAM
See Attached Electronic Search	6/16/2007	MAM
See Attached Electronic Search [updated]	3/30/2008	MAM
See Attached Electronic Search [updated]	8/18/2008	MAM
See Attached Electronic Search [updated]	11/20/2008	MAM
See Interference Search	11/20/2008	MAM